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Contents

 SESSION 1 MATERIAL SELECTION AND CHARACTERIZATION

 7425 02 Optical system material selection using performance indices in a simultaneous optimization approach [7425-01]
 T. Newswander, B. Crowther, Space Dynamics Lab. (United States)

 7425 03 CTE measurements of Cesic®: a low-CTE ceramic composite [7425-02]
 M. R. Krödel, ECM GmbH (Germany); T. Ozaki, Mitsubishi Electric Corp. (Japan)

 7425 04 CTE characterization of ZERODUR® for the ELT century [7425-03]
 R. Jedamzik, T. Döhring, T. Johansson, P. Hartmann, T. Westerhoff, SCHOTT AG (Germany)

 7425 05 Cryogenic refractometer for high accuracy measurements of the refractive index of materials [7425-04]
 P. Spanò, INAF - Osservatorio Astronomico di Brera (Italy); A. Bianco, INAF - Ist. Astrofisica Spaziale e Fisica Cosmica (Italy); G. Toso, INAF - Osservatorio Astronomico di Brera (Italy); G. Pariani, Politecnico di Milano (Italy) and INAF - Osservatorio Astronomico di Brera (Italy)

 SESSION 2 NDE OF SILICON CARBIDE

 7425 06 A general overview of some nondestructive evaluation (NDE) techniques for materials characterization (Invited Paper) [7425-05]
 S. Kenderian, O. Esquivel, K. R. Olson, E. C. Johnson, The Aerospace Corp. (United States)

 7425 07 NDE methods for determining the materials properties of silicon carbide plates [7425-06]
 S. Kenderian, Y. Kim, E. Johnson, I. A. Palusinski, The Aerospace Corp. (United States)

 7425 08 High frequency ultrasound phased array characterization of SiC mirror blanks [7425-07]
 R. A. Haber, A. Portune, Rutgers Univ. (United States)

 7425 09 Material testing of silicon carbide mirrors [7425-08]
 D. B. Witkin, I. A. Palusinski, The Aerospace Corp. (United States)

 SESSION 3 SI-SIC

 7425 0A Proof load testing of lightweight silicon carbide mirror substrates [7425-09]
 M. J. O’Brien, A. De La Cruz, C.-Y. Tang, I. A. Palusinski, The Aerospace Corp. (United States)

 7425 0B Recent achievements using chemical vapor composite silicon carbide (CVC SiC) [7425-10]
 W. A. Goodman, C. Tanaka, Trex Advanced Materials (United States)
7425 0C  Silicon cladding for mirror substrates [7425-11]
C. J. Duston, N. Gunda, Entegris, Inc. (United States); J. R. Schwartz, J. L. Robichaud, L-3
Communications SSG-Tinsley (United States)

7425 0D  Production of mirrors made of HB-Cesic for an airborne reconnaissance telescope system
[7425-12]
M. R. Krödel, P. Hofbauer, ECM GmbH (Germany); G. Luichtel, J. Katzer, M. Tausendfreund,
Carl Zeiss Optronics GmbH (Germany); G. Derst, Dr. Carl Zeiss Jena GmbH (Germany)

7425 0E  Why silicon for telescope mirrors and structures? [7425-13]
R. A. Paquin, D. R. McCarter, McCarter Machine Co., Inc. (United States)

7425 0F  SPIRALE: the first all-Cesic® telescopes orbiting earth [7425-14]
M. R. Krödel, ECM GmbH (Germany); C. Devilliers, Thales Aéria Space (France)

SESSION 4  BERYLLIUM AND BE COMPOSITES

7425 0H  An all-beryllium-aluminum optical system for reconnaissance applications [7425-17]
M. J. Russo, BAE Systems (United States)

7425 0J  Cryogenic adhesive testing for the NIRCam optical bench assembly [7425-19]
M. Jacoby, A. Nordt, Lockheed Martin Space Systems Co. (United States); B. Hurlbut,
Rhombus Consultants Group (United States)

7425 0K  NIRCam optical bench assembly qualification vibration testing [7425-20]
M. Jacoby, A. Nordt, Lockheed Martin Space Systems Co. (United States)

SESSION 5  GLASS

7425 0L  Heritage of ZERODUR® glass ceramic for space applications [7425-21]
T. Döhring, P. Hartmann, F.-T. Lentes, R. Jedamzik, SCHOTT AG (Germany); M. J. Davis,
SCHOTT North America, Inc. (United States)

7425 0M  ZERODUR® glass ceramics for high stress applications [7425-22]
P. Hartmann, K. Nattermann, T. Döhring, R. Jedamzik, M. Kuhro, P. Thomas, SCHOTT AG
(Germany); G. Kling, S. Lucarelli, EADS Astrium GmbH (Germany)

7425 0O  A bonded precision optical assembly using potassium hydroxide [7425-24]
P. V. Mammini, Lockheed Martin Space Systems Co. (United States)

SESSION 6  OPTICAL MATERIALS, PROVEN AND EMERGING

7425 0P  A century of sapphire crystal growth: origin of the EFG method (Keynote Paper) [7425-25]
D. C. Harris, Naval Air Systems Command (United States)

7425 0Q  Silicon nitride for lightweight stiff structures for optical instruments [7425-26]
K. Berroth, FCT Ingenieurkeramik GmbH (Germany); C. Devilliers, Thales Aéria Space
(France); G. Luichtel, Carl Zeiss Optronics GmbH (Germany)
Structural design considerations for an 8-m space telescope [7425-37]
W. R. Arnold, Sr., Jacobs ESTS Group (United States); H. P. Stahl, NASA Marshall Space Flight Ctr. (United States)

Replication of lightweight mirrors [7425-28]
M. Y. Chen, L. E. Matson, Air Force Research Lab. (United States); H. Lee, Air Force Research Lab. (United States) and UES, Inc. (United States); C. Chen, Air Force Research Lab. (United States) and Univ. of Dayton Research Institute (United States)

SESSION 7 THIN FILM COATINGS

Space radiation testing of thin film and multilayer optical coatings [7425-29]
G. E. Thayer, E. L. Blansett, B. E. N. Keeler, Sandia National Labs. (United States)

Fabrication and characterization of cerium oxide thin films for ultraviolet sensing applications [7425-30]
K. Wang, Univ. of Waterloo (Canada) and Thunder Bay Regional Research Institute (Canada); A. Reznik, Thunder Bay Regional Research Institute (Canada); K. S. Karim, Univ. of Waterloo (Canada)

Characterization of silver and aluminum custom mirror coatings for the MRO interferometric telescopes [7425-31]
K. M. McCord, D. A. Klinglesmith III, C. A. Jurgenson, E. J. Bakker, New Mexico Institute of Mining and Technology (United States); R. A. Schmell, R. A. Schmell, D. Gartner, Optical Surface Technologies, LLC (United States); A. Jaramillo, W.M. Keck Observatory (United States); K. Romero, A. Rael, J. Lewis, Optical Surface Technologies, LLC (United States)

POSTER SESSION

Synchrotron radiation x-ray absorption fine-structure and raman scattering studies on 6H-SiC materials [7425-34]
Y.-L. Tu, Z. C. Feng, National Taiwan Univ. (Taiwan); L.-Y. Jang, National Synchrotron Radiation Research Ctr. (Taiwan); W. Lu, Fisk Univ. (United States)

Fabrication of microlens arrays on a glass substrate by roll-to-roll process with PDMS mold [7425-35]
C.-N. Hu, G.-D. J. Su, National Taiwan Univ. (Taiwan)
Conference Committee

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David V. Wick, Sandia National Laboratory (United States)

Session Chairs

1. Material Selection and Characterization
   John W. Pepi, L-3 Communications SSG-Tinsley (United States)

2. NDE of Silicon Carbide
   Iwona A. Palusinski, The Aerospace Corporation (United States)

3. Si-SiC
   William A. Goodman, Trex Enterprises Corporation (United States)
   Matthias R. Krödel, ECM GmbH (Germany)
4 Beryllium and Be Composites
Thomas B. Parsonage, Brush Wellman Inc. (United States)
Rob V. Michel, Brush Wellman, Inc. (United States)

5 Glass
John W. Pepi, L-3 Communications SSG-Tinsley (United States)

6 Optical Materials, Proven and Emerging
Joseph L. Robichaud, L-3 Communications SSG-Tinsley (United States)

7 Thin Film Coatings
Michael J. Ellison, Alpine Research Optics Corporation (United States)